

[0001] The present invention relates, in general, to testing of memory arrays and, more specifically, to a method of efficiently repeating test instructions and to a test controller for use therewith.

[0002] Memory BIST controllers use a very wide instruction word (e.g., 40 bits) for programming algorithms. A memory test developer may specify as many instructions as required in a memory BIST microprogram memory array to perform a memory test. However, since the developer wishes to keep the number of gates required to implement a word in the memory array to a minimum, it is desirable to keep the number of instructions to a minimum. Generally, each word requires about 250 gates.

[0003] Many memory test algorithms, particularly March algorithms, repeatedly perform the same operations but with opposite data or parameters or traverse an address space in one direction and then in the opposite direction. The conventional way of doing this utilizes many more instructions than are required. This requires many more gates than required.

[0004] Kalter et al United States Patent No. 5,961,653 granted on October 5, 1999 for "Processor based BIST for an embedded memory" describes a processor based BIST macro for testing memory embedded in logic and includes a base ROM which is structured to have test instructions written into it in microcode form. The base ROM component is configured having 160 addresses by 34 bits wide, providing for a total of 160 test instructions, branch statements to be used in conjunction with the instructions and a scannable ROM. The scannable ROM is configured having 34 addresses by 34 bits wide. The arrangement allows for altering, adding, deleting, changing the sequence of any test patterns and looping within a single pattern or any group of patterns. The 34 address lines in the scannable ROM allow for 17 branch instructions which bound the beginning and end of each test pattern produced from the base ROM and 17 extra instruction words to accommodate any modifications or changes. The scannable ROM addresses are typically sequenced from 192 through 225. The two ROMs are multiplexed together onto a 34 bit test buss controlled by the sequencer.

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includes a DRAM core, a Microcode or Initial Command ROM, a BIST Engine, a Command Register and a Self-Program Circuit. During self test, the BIST engine may test the DRAM normally until an error is encountered. When an error is encountered, the Self-Program Circuit restarts the self test procedure at less stringent conditions.

SUMMARY OF THE INVENTION

[0008] The present invention provides a method for repeating an instruction or a series of consecutively executed instructions with modifications to the instruction fields of each commands as well as a circuit especially adapted to carry out the method.

[0009] One aspect of the invention is generally defined as a method for testing memory embedded in an integrated circuit, the method comprising executing each instruction of a plurality of test instructions in sequence, each instruction having an inactive repeat control field except for a last instruction of each of one or more groups of one or more instructions to be repeated, each of the last instruction having an active repeat control field; and, for each instruction having an active repeat control field, executing, in sequence, the instructions of the group of instructions with which each instruction is associated for a predetermined number of repeat cycles for the group; and, for each repeat cycle, modifying predetermined fields of each instruction in accordance with a predetermined field modification instructions for each repeat cycle.

[0010] Another aspect of the invention is generally defined as an memory improvement to a test controller for testing a memory array, the controller having a test instruction register array having registers for storing a plurality of test instructions, each register having instruction fields for storing memory addressing sequencing data, write data sequencing data, expect data sequencing data and operation data specifying an operation to be performed on the memory array, the improvement comprising a repeat module for repeating a group of one or more test instructions with modified data, the repeat module including storage means for storing instruction field modification data; and each register of the test instruction register array including an instruction field for enabling or disabling the repeat module.

[0011] A still further aspect of the present invention is generally defined as a test controller for use in testing memory imbedded in an integrated circuit, the test

controller comprising a scannable microcode register array having one or more instruction registers for storing a plurality of test instructions for performing a test of the memory in accordance with a predetermined test algorithm; a pointer controller for selecting one of the test instructions for execution and determining a next
5 instruction for execution in accordance with conditions stored in each the test instruction; an instruction repeat module for reading address sequencing, write data sequencing, expect data sequencing data from a current test instruction and outputting address sequencing, write data sequencing, expect data sequencing data, the repeat module being responsive to instruction repeat data in the current test
10 instruction for repeating an operation specified in the test instruction with different data; a sequencer responsive to an operation code in the current instruction for performing a predetermined operation on the memory under test; and an address generator and a data generator responsive to the output address sequencing, write data sequencing, expect data sequencing data for application to a memory under
15 test in accordance with an operation specified in the current instruction.

BRIEF DESCRIPTION OF THE DRAWINGS

[0012] These and other features of the invention will become more apparent from the following description in which reference is made to the appended drawings
20 in which:

[0013] **Figure 1** is a block diagram view of a portion of a memory test controller including a Repeat Loop microcircuit according to an embodiment of the present invention;

[0014] **Figure 2** is a flow diagram partially illustrating the operation of a pointer controller according to an embodiment of the present invention;
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[0015] **Figure 3** is a block diagram illustrating salient portions of a pointer controller and a scannable microcode memory array according to an embodiment of the present invention;

[0016] **Figure 4** is a block diagrammatic view of a repeat loop module according to an embodiment of the present invention;
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[0017] **Figure 5** is a diagrammatic view of a repeat loop sub-circuit according to an embodiment of the present invention;

[0018] **Figure 6** is a diagrammatic view of a repeat trigger sub-circuit according to an embodiment of the present invention;

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[0019] **Figure 7** is a circuit diagram of a repeat register data processing sub-circuit according to an embodiment of the present invention;

[0020] **Figure 8** is a circuit diagram of a repeat loop instruction field modification sub-circuit according to an embodiment of the present invention;

5 [0021] **Figure 9** is a circuit diagram of an InhibitDataCompare modification circuit according to an embodiment of the present invention; and

[0022] **Figure 10** is a circuit diagram of an InhibitLastAddressCount modification circuit according to an embodiment of the present invention.

10 **DETAILED DESCRIPTION**

[0023] **Figure 1** is a block diagram of portion of a memory test controller **10** according to a preferred embodiment of the present invention in which the test controller is embedded in an integrated circuit. The circuit includes a test interface **12** for loading test instructions and data into the circuit, a Finite State Machine (FSM) **14** which controls the initialization, setup, and initiation of a memory test, a pointer controller **16** which controls the sequencing of test instructions, and a scannable microcode register array **20** for storing a plurality of test instructions, as discussed more fully below. The test controller further includes a data generator **22** and an address generator **24** which operate to execute data and address commands in response to data fields in an active or current microcode instruction which has been loaded for execution, as explained below. A repeat loop module **26** reads the instruction fields of the current instruction and generates memory address and data control signals which are applied to the data generator and address generator. Address generator **24** controls the sequencing of the addresses applied to the memory under test. Data generator **22** provides a programmable write data register (not shown) and a programmable expect data register (not shown). A number of operations can be performed at runtime on these registers to generate a custom data pattern. The write data register controls the data pattern written to the memory under test. The expect data register controls the expected data pattern used to compare with data read from the memory under test. The data and address generators operate independently and are controlled by respective fields of the active microprogram instruction. A sequencer **28** is responsive to an operation field contained in a current test instruction for performing a specified one of a plurality of predetermined operations on the memory under test. Memory address, control signals and data are applied to the memory under test **30** via a memory interface **32**

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which also observes data from the memory under test. In normal operational mode of the circuit, address, data and control signals are applied to the memory interface via inputs generally designated by arrow 36. Data generators, address generators, sequencers and memory interfaces are well known in the art and, accordingly, are not described in detail herein.

Scannable Microcode Register Array

[0024] Scannable microcode register array 20 is comprised of a plurality of serially connected instruction shift-registers. For purposes of illustration, seven registers are shown in **Figure 3**. The number of instructions in the array depends on the specific design requirements and design budget. Each register may be in the order of 34 or more bits and stores a microcode test instruction for execution. The instructions are "ordered" which means that the instructions are executed in sequence. The first address is instruction zero. The instructions stored in the registers perform tests of the memory according to predetermined test algorithms under the control of the pointer controller and the repeat loop module and in accordance with command fields contained in the instructions. An objective of the invention is to enable one to scan in instructions to perform memory tests according to virtually any test algorithm. Thus, the details of the algorithm and of the manner in which data pattern and address sequencing is achieved is not important for the purposes of the present invention and, accordingly, are not described herein.

[0025] Test instructions are serially loaded into the scannable microcode register array 16 via test interface 12. One instruction is executed for each execution of an operation applied to the memory under test by the sequencer. The microcode instructions of the memory BIST controller provide parallel control of blocks such as the address generator, data generator, sequencer and pointer controller, creating a wide but very flexible architecture for the generation of complex test algorithms. The contents of the test instructions in the scannable microcode register array are not modified during a test. The pointer controller, described in more detail later, operates to select an instruction for execution and determines the branch for execution of the next instruction from data contained in each test instruction. Before describing the structure and operation of the various sub-circuits of the test controller, it would be useful to briefly describe the various instruction fields which comprise a microcode instruction. It is to be understood at the outset that additional fields may be provided without departing from the present invention.

Microcode Instruction Field Descriptions

[0026] Each instruction includes at least the following instruction fields:
Address sequencing commands, including Z, X1, X0, Y1, Y0 address segment fields
(referred to as Z_Address_Cmd, X1_Address_Cmd, X0_Address_Cmd,
Y1_Address_Cmd, Y0_Address_Cmd, respectively, later in the description);
OperationSelect; InhibitLastAddressCount; InhibitDataCompare; WriteDataCmd;
ExpectDataCmd; BranchToInstruction; and RepeatLoopControl and
NextConditions.

[0027] Each instruction provides a 2-bit instruction field for each of a Z bank
address segment control field, X1 and X0 row address segment control fields and Y1
and Y0 column address segment control fields for the memory under test. **TABLE I**
shows the address segment control field decodes which apply to all of these fields.
Actions such as increment or decrement can be performed on each address
segment independently. The decodes are arranged in pairs so that a command can
be changed to its opposite or complement value simply reversing the least significant
bit.

TABLE I Address Segment Control Field Decode	
Field Value	Instruction Description
00	Hold
01	Hold
10	Increment
11	Decrement

[0028] The InhibitLastAddressCount field is a single bit field which, when
active, prevents an address counter from counting the next address on a True
NextConditions.

[0029] The WriteDataCmd control field is a 3-bit field which is decoded to
select the data or perform an operation on a data register which is applied to the
memory for a write operation. It will be noted that the decodes are arranged in pairs
in which the only difference between the bit values of members of the pairs is the

values of the least significant bit. The repeat loop module uses this characteristic in a manner explained later. The field decode is shown in **TABLE III**.

TABLE III WriteDataCmd Instruction Field Decode	
Field Value	Instruction Description
000	Select the WriteData Register
001	Select the WriteData Register and Invert
010	Select the register containing all zeroes
011	Select the register containing all ones
100	Select and Rotate the WriteData Register
101	Select and Rotate the WriteData Register and Invert
110	Select and Rotate the WriteData Register with Inverted feedback
111	Select and Rotate the WriteData Register with Inverted feedback and Invert

[0030] The ExpectDataCmd instruction field is a 3-bit field which is decoded to select the expect data or to perform an operation on an expect data register for comparison on a read operation. The ExpectDataCmd field decodes are identical to the WriteDataCmd field and are shown in **TABLE IV**.

TABLE IV
ExpectDataCmd Instruction Field Decode

	Field Value	Instruction Description
5	000	Select the ExpectData Register
	001	Select the ExpectData Register and Invert
	010	Select the register containing all zeroes
	011	Select the register containing all ones
	100	Select and Rotate the ExpectData Register
10	101	Select and Rotate the ExpectData Register and Invert
	110	Select and Rotate the ExpectData Register with Inverted feedback
	111	Select and Rotate the ExpectData Register with Inverted feedback and Invert

[0031] The InhibitDataCompare field is a single-bit instruction field which, when set, disables any StrobeDataOut signal during execution of the specified operation. When not set, normal comparison of expected data and read data from the memory under test is performed.

[0032] The OperationSelect field specifies the operation to be applied to the memory under test. The length of the OperationSelect field is dependant on the number of operations defined by the test algorithm designer. This field is applied to and used by the sequencer which is designed to perform all of the desired operations.

[0033] The BranchToInstruction field identifies the instruction which the pointer control selects as the next instruction for execution if any of the requested NextConditions triggers, apart from the RepeatLoopDone condition, are not true.

[0034] The RepeatLoopControl instruction field is a 2-bit field with an instruction decode given below. As explained more fully later, the repeat loop module includes two 2-bit counters. As indicated in the RepeatLoopControl field decodes shown in **TABLE II**, each counter can be incremented separately or the two counters may be chained together to form one 4-bit counter and incremented sequentially. Thus, the instruction decode from the RepeatLoopControl field defines the counter configuration. The RepeatLoopDone condition, described below, is always required to increment a repeat operation if the instruction decode from the

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Pointer Controller

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Figure 2 illustrates the branch decision tree of the pointer controller. As illustrated, the prioritization of testing conditions for determining the branch are as follows, from highest priority to lowest priority:

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[0046] Branch To Instruction: Branch to the instruction identified by the BranchToInstruction field in the executing instruction.

Otherwise, the RepeatLoopConditions_True flag is set to logic 0 and control passes to a Repeat Loop Conditions compare block 42. Block compares the content of the RepeatLoopControl field of the current instruction against the RepeatLoopControl decodes shown in TABLE II. If it matches one of the three RepeatLoopControl decodes, 01, 10, and 11, a RepeatLoop_Conditions_True signal is set to logic 1 and the instruction at the appropriate RepeatLoop_BranchTo-Instruction address is selected and the corresponding instruction is loaded into instruction execution register 34. Otherwise, signal RepeatLoop_Conditions_True is set to logic 0 and the address specified in the BranchToInstruction field of the current instruction is loaded into the instruction address register and the corresponding instruction is loaded into instruction execution register 34.

[0047] **Figure 3** is a block diagram of the architecture of the pointer controller **16**. The Figure illustrates microcode array **20** as having eight instruction registers labeled "Instruction 0" through "Instruction 7". An instruction select multiplexer **46** is responsive to the output of a Next Instruction Determining Block **44**. The figure further illustrates instruction execution register **34**, instruction address register **38**, and NextConditions compare block **40**. Compare block **40** outputs the aforementioned RepeatLoop_Conditions_True signal and the Next_Conditions_True signal to block **44**. The contents of the NextConditions field of the instruction in register **34** are applied to block **40** and the contents of the BranchToInstruction field of the current instruction are applied to block **44**. A RepeatLoop_BranchTo-Instruction address output by the repeat loop module, as described later with reference to **Figure 7**, is applied to block **44**. Finally, the address of the current

instruction is incremented at 48 and applied to block 44. The microprogram address is always initialized to address "zero" (Instruction 0) prior to executing any of the microcode instructions. A LastStateDone signal is returned to the Finite State Machine on a True NextConditions when a microprogram address has completed execution of the last available instruction.

Repeat Loop Module

[0048] Repeat loop module 26 provides optimal coding for redundant or symmetric sub-test sequences. Without the repeat loop module, a much larger number of instructions would be required to perform a memory test. The repeat loop module is used to repeat execution of a group of one or more sequential instructions. A group of sequential instructions includes the instructions between and including an instruction specified by a repeat loop module BranchToInstruction register and the instruction which initiates the repeat operation. This group of sequential instructions is re-executed a plurality of times, with each instruction being modified in accordance with a set of modification commands for each repeat sequence or cycle. The repeat loop module may include one or more repeat loop circuits described later. The specific embodiment illustrates herein include two repeat loop circuits.

Modification Commands

[0049] In the embodiment illustrated herein, the modification commands comprise a set of five bits, one bit for each of Address sequencing, WriteData sequencing, ExpectData sequencing, InhibitDataCompare and InhibitLastAddressCount fields. Each modification bit has a value of logic 0 or logic 1. The modification bit for the address segment, WriteDataCmd and ExpectDataCmd fields, a value of logic 0 means that the instruction field is to remain unchanged. A value of logic 1 means to the least significant bit of a corresponding instruction field is to be changed to its complimentary value. When set to logic 1, the InhibitLastAddressCount modification bit overrides the InhibitLastAddressCount instruction field for the instruction containing the corresponding RepeatLoopControl command. The InhibitDataCompare modification bit overrides the InhibitDataCompare Instruction bit for all instructions which form part of the group of repeated instructions.

[0050] The single address sequence modification bit applies to all of the address segment instruction fields and specifies that each of the address segment

commands executed by instructions during a repeat operation will either be executed as specified by the instruction field or the command will be modified to a complimentary command. Similarly, WriteDataCmd and ExpectDataCmd modification bits specify that the WriteDataCmd and ExpectDataCmd fields, respectively, executed by instructions during a repeat operation will either be executed as specified by the instruction or the command will be modified to a complimentary command.

[0051] The InhibitLastAddressCount modification bit provides for a reverse address sequence on the next instruction without requiring an additional instruction to change the address pointer. Valid values are logic 0 by which any address segment command to increment or decrement is executed normally and logic 1 which prevents a selected address register from counting on the last execution of the selected instruction when all requested NextConditions are True and the next sequential instruction is loaded for execution.

[0052] The InhibitDataCompare modification bit overrides the InhibitDataCompare instruction field. Valid values are logic 0 where expected data and read data are compared normally and logic 1 by which any StrobeDataOut signal is disabled, and the expect data and read data are not compared.

Repeat Procedure

[0053] A repeat procedure comprises executing, in sequence, a previously executed instruction or a group of sequentially executed instructions for a predetermined number of repeat cycles. The first execution of an instruction or a group of sequential instructions is performed unmodified, i.e., as the instruction was programmed.

[0054] To cause an instruction or a group of sequential instructions to be repeated, the last instruction of the group is arranged such that its RepeatLoopDone bit is set to "1" and its RepeatLoopControl field is set to the appropriate one of the three loop incrementing codes shown in **TABLE II**, i.e., "01", "10" or "11". In all other instructions of the group, including the first instruction, the RepeatLoopDone bit is set to "0" and the RepeatLoopControl field is set to Idle, "00"; the address of the first instruction of the group is stored in a repeat loop branch-to-instruction register; a value indicating the number of repeat sequences or cycles to be performed is stored in a maximum count register; and a set of modification bits for each repeat sequence is stored in a corresponding or associated modification bit register.

[0055] To cause one group of instructions to be nested within another group, the same steps are performed for the second group, using a separate repeat loop branch-to-instruction register, maximum count register, and modification bit registers.

[0056] When the last instruction of a repeat operation is loaded, the RepeatLoopControl specified in the last instruction is performed. This causes the instruction specified in the repeat loop branch-to-instruction to be loaded and executed, followed by the loading and execution of all subsequent instructions until the last instruction is again loaded. This operation continues until the number of repeat sequences equals the value stored in the maximum count register.

[0057] In the first repeat cycle, the instructions in the group are executed without modification. On each subsequent repeat cycle, instruction fields are modified according to a corresponding set of modification bits. When more than one repeat operation is in progress, the manner in which instruction fields are modified must be adjusted to accommodate the modification bits specified for the two or more active repeat operation. This is described in detail later with reference to **Figure 8-10**. An instruction has completed execution when the sequencer has completed the operation specified in the OperationSelect field of the current instruction. The sequencer signals completion of the operation by generating an active LastTick signal.

Repeat Loop Module Structure

[0058] **Figure 4** illustrates a block diagram of a Repeat Loop Module according to a preferred embodiment of the present invention. Repeat loop module **26** generally comprises a Repeat Loop Circuit **50**, a Generate Repeat Loop Done circuit **52**, a select repeat loop BranchToInstruction circuit **53**, and an instruction field modification circuit **54**. The 2-bit RepeatLoopControl field is input to the repeat loop circuit **50** which decodes and executes the code. The two other inputs to repeat loop circuit **50** are the RepeatLoop_Conditions_True signal from the pointer control module **16** and the LastTick signal from sequencer module **28**. The RepeatLoopControl field also controls generate repeat loop done circuit **52** and instruction field modification circuit **54**. Generate repeat loop done circuit **52** generates the RepeatLoopDone signal which is used by the Pointer Controller **16**. The RepeatLoopDone signal remains inactive until a RepeatLoopControl has reached the last repeat cycle at which point the RepeatLoopDone signal becomes active and remains active until the selected repeat loop is reset. Select repeat loop

BranchToInstruction circuit **53** specifies the instruction pointer used by Pointer Controller **16** to determine the next instruction to be loaded into the instruction execution register.

5 Repeat Loop Circuit

[0059] **Figure 5** illustrates the architecture of Repeat Loop circuit **50**. The repeat loop circuit architecture comprises a Command Decoder **55** and two nearly identical units called Repeat Loop A and Repeat Loop B. Command Decoder **55** receives the 2-bit RepeatLoopControl signal from the instruction in instruction execution register **34**. The RepeatLoopControl generates the binary signal values given in **TABLE V** for signals IncCntrA, IncCntrB, IncCntrBA when decoded:

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TABLE V			
RepeatLoopControl	IncCntrA	IncCntrB	IncCntrBA
00	0	0	0
01	1	0	0
10	0	1	0
11	0	0	1

[0060] The 2-bit RepeatLoopControl field is decoded to perform one of four functions in the repeat loop circuit as specified in **TABLE II**. '00' performs a HOLD function which does not change the state of the repeat loop circuit; '01' instructs 2-bit counter **71** in Repeat Loop A to count; '10' instructs 2-bit counter **60** in Repeat Loop B to count; and '11' instructs counter **60** in Repeat Loop B and counter **71** in Repeat Loop A to count in such a manner that the two 2-bit counters form a single 4-bit counter. In this 4-bit counter, counter **71** from Repeat Loop A contains the two least significant bits and counter **60** from Repeat Loop B contains the two most significant bits.

[0061] Repeat Loop B is comprised of three AND gates **56**, **58**, and **59**, one OR gate **57**, 2-bit counter **60**, four 5-bit repeat loop registers **61**, **62**, **63**, and **64**, a 4-to-1 multiplexer **65**, a 2-bit comparator **66**, and a 2-bit LoopCountBMax register **67**. AND gates **56** and **59** and OR gate **57** perform the logic function:

IncCntrBA AND Loop_CntrA_Max

OR

IncCntrB AND LoopStateTrue AND LastTick.

35 This logic function enables counter **60** to increment the count value by one when RepeatLoopControl specifies incrementing counter BA and Repeat Loop Counter A

5 issued. AND gate 59 performs the logic function:

Signal Loop_CntrB_Max is the output of comparator **66** which compares the count value from the counter **60** with the maximum count value initialized in the

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10     counter has reached the maximum count value initialized in the LoopCountBMax
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to select one of four 5-bit repeat registers **61**, **62**, **63**, or a register **64** containing all zeros. Initially, register **64** is selected because counter **60** is reset and contains the

15 to-1 multiplexer **65**. When the output of counter **60** is '10', register **62** is the output of

[0062] Repeat Loop A is comprised of two AND gates **69**, and **70**, one OR gate **68**, 2-bit counter **71**, four 5-bit repeat loop registers **72**, **73**, **74**, and **75**, a 4-to-1 multiplexer **76**, a 2-bit comparator **77**, and a 2-bit LoopCountAMax register **78**. AND gate **69** and OR gate **68** perform the logic function:

This logic function enables counter **71** to increment its count value by one when the RepeatLoopControl field specifies incrementing counter BA OR when the

25 RepeatLoopControl specifies incrementing counter **71**. Again, the remaining two

The signal Loop_CntrA_Max is the output of the comparator **77** which compares the count value from counter **71** with the maximum count value initialized in

LoopCountAMax register **78**. This logic function resets the counter **71** to '00' when the counter has reached the maximum count value initialized in LoopCountAMax register **78**.

[0063] The output of counter **71** is the select input of the 4-to-1 multiplexer used to select one of the four 5-bit repeat registers **72**, **73**, **74**, and a register **75** containing all zeros. Initially the register **75** is selected because counter **71** is reset and contains the value '00'. When the output of counter **71** value is '01', the register **72** is the output of the 4-to-1 multiplexer; when the output of counter **71** value is '10', register **73** is the output of the multiplexer; when the output of counter **71** value is '11', register **74** is the output of the multiplexer.

Repeat Loop Done Circuit

[0064] Repeat loop done circuit **52**, illustrated in **Figure 6**, generates control signal, RepeatLoopDone, which is input to pointer controller **16**. The RepeatLoopDone signal is used in pointer controller **16** to indicate whether repeat loop module **26** has completed execution (logic 1) or has not completed (logic 0). As shown in **Figure 6**, the circuit comprises a three-input AND gate **80**, two 2-input AND gates **81** and **82**, and a 3-input OR gate **84**. The inputs to the repeat loop done circuit are IncCntrBA signal from command decoder **55**, the Loop_CntrA_Max signal generated by comparator **78**, and the Loop_CntrB_Max signal from comparator **67**. AND gate **80** performs a logical AND of signals IncCntrBA, Loop_CntrA_Max, and Loop_CntrB_Max, indicating when both repeat loop counters **60** and **71** have reached their respective maximum values and the repeat loop command is "11". AND gate **81** performs a logical AND of the signals IncCntrB and Loop_CntrB_Max indicating when counter **60** has reached its maximum value and the RepeatLoopControl command is '10'. AND gate **82** performs a logical AND of signals IncCntrA and Loop_CntrA_Max indicating when repeat loop counter **71** has reached the maximum value and the RepeatLoopControl command is '01'. OR gate **84** performs a logical OR of the outputs of AND gates **80**, **81** and **82**. The output of OR gate **83** is the RepeatLoopDone signal. These gates perform the logic function:

$$\begin{aligned} & \text{IncCntrBA AND Loop_CntrA_Max AND Loop_CntrB_Max} \\ & \text{OR} \\ & (\text{IncCntrB AND Loop_CntrB_Max}) \\ & \text{OR} \\ & (\text{IncCntrA AND Loop_CntrA_Max}) \end{aligned}$$

[0065] Select Repeat Loop BranchToInstruction

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Figure 3) is logic 1. When only Repeat Loop A is active, the address of the first

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[0067] OR gate **87** performs a logical OR of the output of AND gate **86** and the IncCtrB signal. The output of OR gate **87** is the select signal for 2-to-1 multiplexer **88**. The select signal for multiplexer **88** selects RepeatLoopA_Branch-

ToInstruction **84** register or the RepeatLoopB_BranchToInstruction register **85**. Registers **84** and **85** each contain an instruction address which is selected by multiplexer **88**. The output of multiplexer **88** is the RepeatLoop_BranchToInstruction signal.

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Instruction Field Modification Circuit

[**0068**] Instruction field modification circuit **54** performs instruction field modifications to the following fields in the executing instruction: Z_Address_Cmd, X1_Address_Cmd, X0_Address_Cmd, Y1_Address_Cmd, Y0_Address_Cmd, WriteDataCmd, ExpectDataCmd, InhibitDataCompare, and InhibitLastAddressCount. The modifications to these instruction fields is dependant on the selected register from Loop A and the selected register from Loop B of repeat loop circuit **50**. When a bit in the selected register of Loop A is a logic '1', the corresponding instruction field is to be modified and when the bit is a logic '0', the corresponding instruction field is to not be modified. The same applies to the selected register of Loop B.

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[**0069**] As shown in **Figure 8**, the Instruction Field Modification Circuit **54** comprises ten XOR gates **89, 90, 91, 92, 93, 94, 95, 96, 97, 98**, an InhibitDataCompare modification circuit **99**, and an InhibitLastAddressCount modification Circuit **100**.

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[**0070**] Bit 4 from the selected Loop A register and of the selected Loop B register modify bit 0 of the ExpectDataCmd instruction field. As previously discussed, the ExpectDataCmd instruction field is a 3-bit field with up to eight unique decodes. These eight ExpectDataCmd decodes are paired such that the function of a given decode and its complement function differ only with bit 0 of the

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ExpectDataCmd field. Thus, modifying bit 0 of the ExpectDataCmd field results in the complement function replacing the function instructed to be performed by the ExpectDataCmd field. EXCLUSIVE-OR gate **97** performs a logical XOR between bit 4 of the selected Loop A register and bit 4 of the selected Loop B register. Since there are multiple repeat loop structures which may be nested, bit 4 of the selected Loop B register and bit 4 of the selected Loop A register are EXCLUSIVE-ORed.

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[**0071**] If selected Loop A register bit 4 is 0 and selected Loop B register bit 4 is '0', the output of XOR gate **97** is '0', indicating that no modification is required. If the selected Loop A register bit 4 is '0' and selected Loop B register bit 4 is '1', the output of the XOR gate **97** is '1', indicating that a modification is required. Similarly, if the selected Loop A register bit 4 is '1' and the selected Loop B register bit 4 is '0',

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the output of the XOR gate 97 is '1', indicating that a modification is required. If the selected Loop A register bit 4 is '1' and selected Loop B register bit 4 is '1' the output of the XOR gate 97 is '0', indicating that both repeat loops require a modification which cancel each other out and no modification is performed. XOR gate 98 performs the inversion of the ExpectDataCmd field bit 0 when the output of XOR gate 97 is a '1'. When the output of XOR gate 97 is '0', bit 0 of the ExpectDataCmd field remains unchanged.

[0072] Bit 3 from the selected Loop A register and selected Loop B register modifies the WriteDataCmd instruction field bit 0. As previously discussed, the WriteDataCmd instruction field is a three-bit field with up to eight unique decodes. The eight WriteDataCmd decodes are paired such that the function of a given decode and its complement function differ only with bit 0 of the WriteDataCmd field. Thus, modifying bit 0 of the WriteDataCmd field results in the complement function replacing the function instructed to be performed by the WriteDataCmd field.

EXCLUSIVE-OR gate 95 performs a logical XOR between the bit 3 of the selected Loop A register and bit 3 of the selected Loop B register. Since there are multiple repeat loop structures which may be nested, both the selected Loop B register bit 3 and the selected Loop A register bit 3 are EXCLUSIVE-ORed.

[0073] If selected Loop A register bit 3 is '0' and selected Loop B register bit 3 is '0', the output of the XOR gate 95 is '0', indicating that no modification is required. If bit 3 of the selected Loop A register is '0' and bit 3 of the selected Loop B register is '1', the output of the XOR gate 95 is '1', indicating that a modification is required. If bit 3 of the selected Loop A register is '1' and bit 3 of the selected Loop B register is '0', the output of the XOR gate 95 is '1', indicating that a modification is required. If bit 3 of the selected Loop A register is '1' and bit 3 of the selected Loop B register is '1', the output of the XOR gate 95 is '0', indicating that both repeat loops require a modification which cancel each other out and, therefore, no modification is performed. XOR gate 96 performs the inversion of the WriteDataCmd field bit 0 when the output of XOR gate 95 is a '1'. When the output of XOR gate 95 is '0', bit 0 of the WriteDataCmd field remains unchanged.

[0074] Bit 2 from the selected Loop A register and selected Loop B register modify bit 0 of the address instruction fields, Z_AddressCmd, X1_AddressCmd, X0_AddressCmd, Y1_AddressCmd, and Y0_AddressCmd. As previously discussed, the address command fields for the address segments Z, X1, X0, Y1, and Y0 are two-bit fields with each having up to four unique decodes. These four decodes are

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InhibitDataCompare Modification Circuit

[0077] InhibitDataCompare Modification Circuit 99 performs the InhibitDataCompare instruction modifications. The modifications to these instruction fields is dependant on the selected Loop A register bit 0 signal and the selected Loop B register bit 0 signal from the Instruction Field modification circuit 54. The InhibitDataCompare instruction bit from the pointer controller 16 is replaced with the combination of bits from the selected Loop A register bit 0 and the selected Loop B register bit 0 signals.

[0078] As shown in Figure 9, InhibitDataCompare Modification Circuit 99 comprises one XOR gate 101, three OR gates 102, 103, and 104, and a 2-to-1 multiplexer 105. The select input for multiplexer 105 is the output of the OR-tree comprising of the OR gates 102, 103, and 104. The OR tree detects if either of repeat loop A counter 71 or repeat loop B counter 60 is active or contains values greater than zero. If either of the repeat loop counters has a value greater than zero, the output of the OR gate 104 is a logic '1' and the multiplexer selects the output of the XOR gate 101. The XOR gate 101 combines bit 0 of the selected Loop A register and bit 0 of the selected Loop B register. If both of the repeat loop counters have a value of zero, the output of the OR gate 104 is a logic '0' and the multiplexer selects the InhibitDataCompare instruction command field from the pointer controller 16.

InhibitLastAddressCount Modification Circuit

[0079] InhibitLastAddressCount Modification Circuit 100 performs the InhibitLastAddressCount instruction field modifications. The InhibitLastAddressCount instruction bit from the pointer controller 16 is replaced with either the selected Loop A register bit 0 or the selected Loop B register bit 0 depending on which repeat loop is active.

[0080] As shown in Figure 10, InhibitLastAddressCount Modification Circuit 100 comprises five OR gates 107, 110, 114, 117, and 118, and six AND gates 106, 108, 109, 112, 114, and 116, NAND gate 113, and NOR gate 111. Only one of the three signals InhibitLastAddressCount, selected Loop A register bit 0, or selected Loop B register bit 0 is passed through the circuit at any given moment. These three signals are combined utilizing OR gate 118 since the active level of the Modified_InhibitLastAddressCount is a logical '1'. The output of the OR gate 118 is

[0081] The first bit which may be passed through the circuit to drive the Modified_Inhibit-LastAddressCount signal is bit 0 from the selected Loop A register.

[0082] The second bit which may be passed through the circuit to drive the Modified_Inhibit_LastAddressCount signal is bit 0 from the selected Loop B register. This bit passes through the circuit on the last execution of a repeat loop, before the repeat loop B counter **60** increments. This bit is selected utilizing OR gates **107** and **110**, and two AND gates **106** and **108**. The output of AND gate **106** performs a logical OR in OR gate **107** when the repeat loop command to repeat circuit **50** is logical '10' to increment repeat loop B counter. If either of these conditions is true, the output of OR gate **107** performs a logical AND in gate **108** which ensures that the InhibitLastAddressCount field replacement occurs only when repeat loop B counter **60** is greater than zero and the LoopStateTrue condition from the pointer controller **16** is logical '1'. The output from AND gate **108** then proceeds to AND gate **109** which gates bit 0 of the selected Loop B register to OR gate **118**.

[0083] The third bit which may be passed through the circuit to drive the Modified_Inhibit LastAddressCount signal is the InhibitLastAddressCount signal from the pointer controller **16**. This bit passes through the circuit when neither of the above two bits is enabled to pass through. This bit is selected utilizing NOR gate**111**

and AND gate **112**. NOR gate **111** ensures that neither of selected Loop A register bit 0 nor selected Loop B register bit 0 conditions enabling them to pass through the circuit is True. The output of NOR gate **111** proceeds to the AND gate **112** which gates the InhibitLastAddressCount signal to the OR gate **118**.

- 5 **[0084]** Although the present invention has been described in detail with regard to preferred embodiments and drawings of the invention, it will be apparent to those skilled in the art that various adaptations, modifications and alterations may be accomplished without departing from the spirit and scope of the present invention. Accordingly, it is to be understood that the accompanying drawings as set forth
- 10 herein above are not intended to limit the breadth of the present invention, which should be inferred only from the following claims and their appropriately construed legal equivalents.

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